

Tentative

CM200RL-12NF

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Apr.	T.Furuie 27-Nov.-'03			ku.Takata 17-Jun.-'04

HIGH POWER SWITCHING USE

Notice : This is not a final specification. Some parametric limits are subject to change.

CM200RL-12NF
● I_c200A
● V_{CES} 600V
●Insulated Type
●7-elements in a pack

APPLICATION

AC drive inverters & Servo controls, etc

ABSOLUTE MAXIMUM RATINGS ($T_j = 25\text{ }^\circ\text{C}$)

Inverter part

Symbol	Item	Conditions	Ratings	Units
V_{CES}	Collector-emitter voltage	G-E Short	600	V
V_{GES}	Gate-emitter voltage	C-E Short	± 20	
I_c	Collector current	DC, $T_c=88\text{ }^\circ\text{C}^*1$	200	A
I_{CM}		Pulse ②	400	
I_E ①	Emitter current		200	
I_{EM} ①		Pulse ②	400	
P_c ③	Maximum collector dissipation	$T_c=25\text{ }^\circ\text{C}$	890	W

Brake part

Symbol	Item	Conditions	Ratings	Units
V_{CES}	Collector-emitter voltage	G-E Short	600	V
V_{GES}	Gate-emitter voltage	C-E Short	± 20	
I_c	Collector current	DC, $T_c=99\text{ }^\circ\text{C}^*1$	100	A
I_{CM}		Pulse ②	200	
P_c ③	Maximum collector dissipation	$T_c=25\text{ }^\circ\text{C}$	540	W
V_{RRM}	Repetitive peak reverse voltage	Clamp diode part	600	V
I_{FM}	Forward current	Clamp diode part	100	A

(Common rating)

Symbol	Item	Conditions	Ratings	Units
T_j	Junction temperature		$-40\sim+150$	$^\circ\text{C}$
T_{stg}	Storage temperature		$-40\sim+125$	
Viso	Isolation voltage	Main terminal to base plate, AC 1 min.	2500	V
—	Torque strength	Main terminal M5	2.5~3.5	N·m
—	Torque strength	Mounting holes M5	2.5~3.5	
—	Weight	Typical value	750	g

ELECTRICAL CHARACTERISTICS ($T_j = 25\text{ }^\circ\text{C}$)

Inverter part

Symbol	Item	Conditions	Min.	Typ.	Max.	Units	
I_{CES}	Collector cutoff current	$V_{CE}=V_{CES}, V_{GE}=0V$	—	—	1	mA	
$V_{GE(th)}$	Gate-emitter threshold voltage	$I_C=20mA, V_{CE}=10V$	6	7	8	V	C
I_{GES}	Gate leakage current	$V_{GE}=V_{GES}, V_{CE}=0V$	—	—	0.5	μA	
$V_{CE(sat)}$	Collector to emitter saturation voltage	$I_C = 200A$	—	1.7	2.2	V	
		$V_{GE}=15V$	—	1.7	—		
C_{ies}	Input capacitance	$V_{CE}=10V$ $V_{GE}=0V$	—	—	30	nF	
C_{oes}	Output capacitance		—	—	3.7		
C_{res}	Reverse transfer capacitance		—	—	1.2		
Q_G	Total gate charge	$V_{CC}=300V, I_C=200A, V_{GE}=15V$	—	800	—	nC	
$t_{d(on)}$	Turn-on delay time	$V_{CC}=300V, I_C=200A$ $V_{GE1}=V_{GE2}=15V$ $R_G=3.1\Omega$, Inductive load switching operation $I_E=200A$	—	—	120	ns	B
t_r	Turn-on rise time		—	—	100		
$t_{d(off)}$	Turn-off delay time		—	—	300		
t_f	Turn-off fall time		—	—	300		
t_{rr} ①	Reverse recovery time		—	—	150		
Q_{rr} ①	Reverse recovery charge	—	4.8	—	μC	B	
V_{EC} ①	Emitter-collector voltage	$I_E=200A, V_{GE}=0V$	—	—	2.8	V	C
$R_{th(j-c)Q}$	Thermal resistance	IGBT part (1/6 module) ^{*1}	—	—	0.14	$^\circ C/W$	
$R_{th(j-c)R}$	Thermal resistance	FWDi part (1/6 module) ^{*1}			0.22		
$R_{th(c-f)}$	Contact thermal resistance	Case to fin, Thermal compound Applied (1/6module) ^{*2}	—	0.051	—		
R_G	External gate resistance		3.1	—	31	Ω	

Brake Part

Symbol	Item	Conditions	Min.	Typ.	Max.	Units
I_{CES}	Collector cutoff current	$V_{CE}=V_{CES}, V_{GE}=0V$	—	—	1	mA
$V_{GE(th)}$	Gate-emitter threshold voltage	$I_C=10mA$	6	7	8	V
I_{GES}	Gate leakage current	$V_{GE}=V_{GES}, V_{CE}=0V$	—	—	0.5	μA
$V_{CE(sat)}$	Collector to emitter saturation voltage	$T_j=25^\circ C$	—	1.7	2.2	V
		$I_C=100A$				
		$T_j=125^\circ C$	—	1.7	—	
C_{ies}	Input capacitance	$V_{CE}=10V$ $V_{GE}=0V$	—	—	15	nF
C_{oes}	Output capacitance		—	—	1.9	
C_{res}	Reverse transfer capacitance		—	—	0.6	
Q_G	Total gate charge	$V_{CC}=300V, I_C=100A, V_{GE}=15V$	—	400	—	nC
V_{FM}	Forward voltage drop	$I_F=100A$			2.8	V
$R_{th(j-c)Q}$	Thermal resistance	IGBT part *1	—	—	0.23	$^\circ C/W$
$R_{th(j-c)R}$		Clamp diode part *1	—	—	0.41	

*1: T_c measured point is just under the chips.

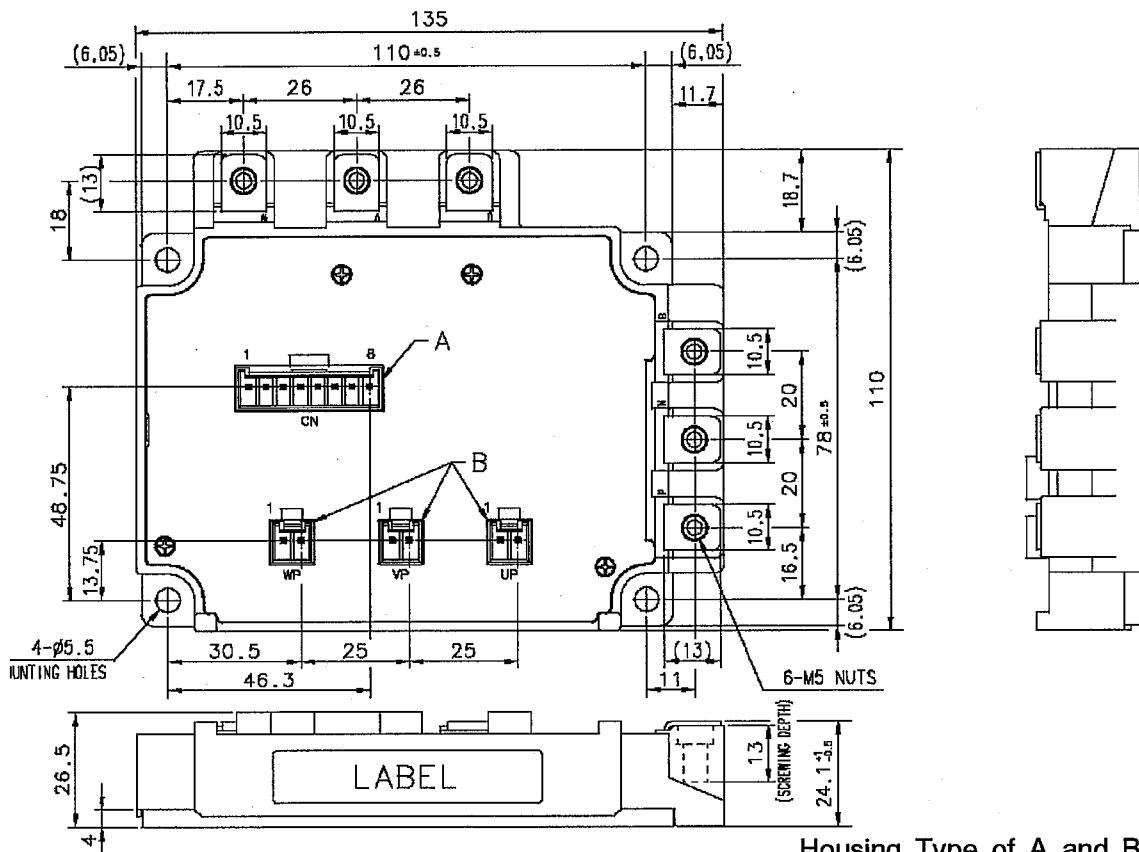
If you use this value, $R_{th(f-a)}$ should be measured just under the chips.

*2: Typical value is measured by using Shin-etsu Silicone "G-746".

- ① $I_E, V_{EC}, t_{rr}, Q_{rr}$ represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWDi).
- ② Pulse width and repetition rate should be such that the device junction temp. (T_j) dose not exceed T_{jmax} rating.
- ③ Junction temperature (T_j) should not increase beyond $150^\circ C$.
- ④ Pulse width and repetition rate should be such as to cause negligible temperature rise.

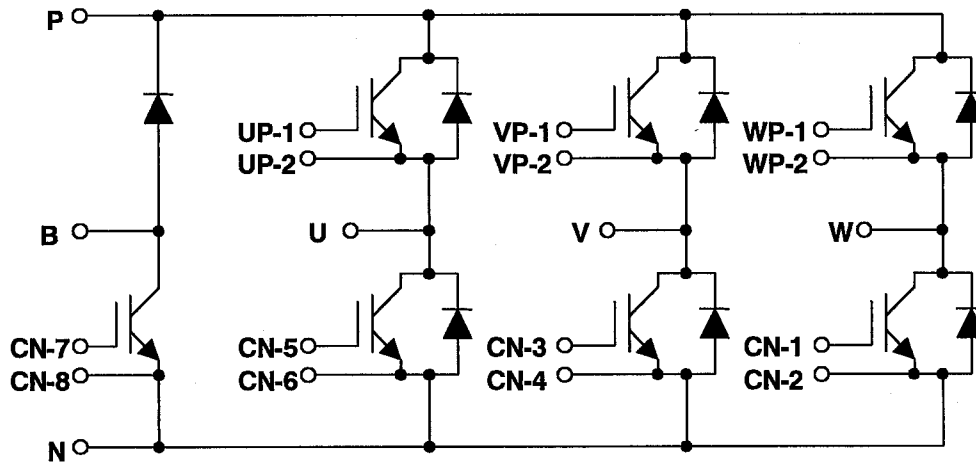
OUTLINE DRAWING

Dimensions in mm



Housing Type of A and B
 (J.S.T.Mfg.Co.Ltd)
 A= B8P-VH-FB-B, B= B2P-VH-FB-B

CIRCUIT DIAGRAM



CHIP LAYOUT DRAWING

Dimensions in mm

